Texas Instruments

Data sheet acquired from Harris Semiconductor
SCHS025

CD4015B Types

CMOS Dual 4-Stage Static Shift Register

With Serial Input/Parallel Output

High-Voltage Types (20-Volt Rating)

■ CD4015B consists of two identical, independent, 4-stage serial-input/parallel-output registers. Each register has independent CLOCK and RESET inputs as well as a single serial DATA input. "Q" outputs are available from each of the four stages on both registers. All register stages are D-type, master-slave flip-flops. The logic level present at the DATA input is transferred into the first register stage and shifted over one stage at each positive-going clock transition. Resetting of all stages is accomplished by a high level on the reset line. Register expansion to 8 stages using one CD4015B package, or to more than 8 stages using additional CD4015B's is possible.

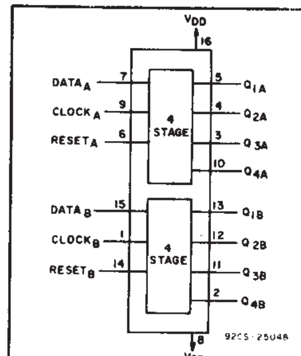
The CD4015B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic package (E suffix), and in chip form (H suffix).

Features:

- **Medium speed operation . . . .**
  12 MHz (typ.) clock rate at $V_{DD} - V_{SS}$ = 10 V
- **Fully static operation**
- **8 master-slave flip-flops plus input and output buffering**
- **100% tested for quiescent current at 20 V**
- **5-V, 10-V, and 15-V parametric ratings**
- **Standardized, symmetrical output characteristics**
- **Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C**
- **Noise margin (full package-temperature range) =**
  1 V at V_{DD} = 5 V
  2 V at V_{DD} = 10 V
  2.5 V at V_{DD} = 15 V
- **Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"**

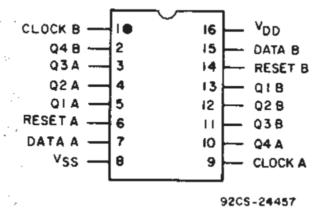
Applications:

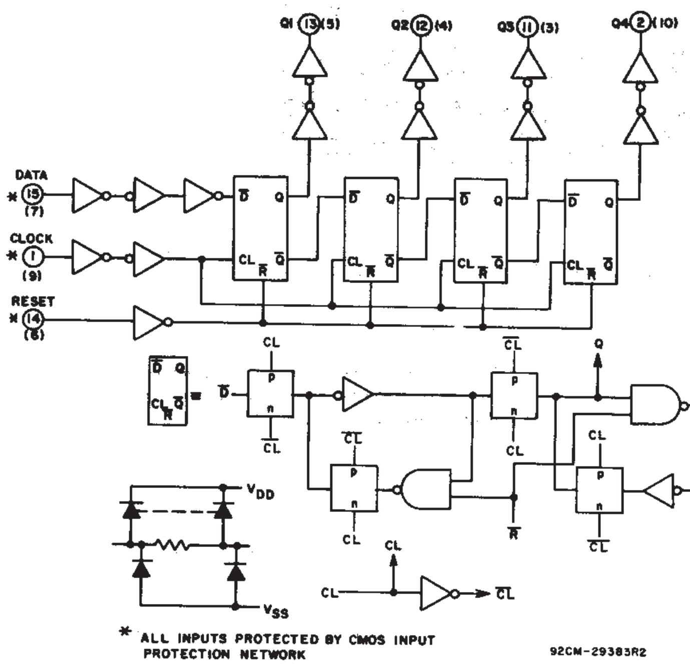
- **Serial-input/parallel-output data queueing**
- **Serial to parallel data conversion**
- **General-purpose register**



CD4015B FUNCTIONAL DIAGRAM

TERMINAL DIAGRAM





TRUTH TABLE

CL	D	R	Q_1	Q_n
↗	0	0	0	Q_{n-1}
↗	1	0	1	Q_{n-1}
↘	X	0	Q_1	Q_n (NO CHANGE)
X	X	1	0	0

X = DON'T CARE CASE

Fig. 1 – Logic diagram (1 register).

MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD})
Voltages referenced to V_{SS} Terminal) .... −0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS .... −0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT .... ±10mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = −55°C to +100°C 500mW
For T_A = +100°C to +125°C .... Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) 100mW
OPERATING-TEMPERATURE RANGE (T_A) .... −55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg}) .... −65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max .... +265°C

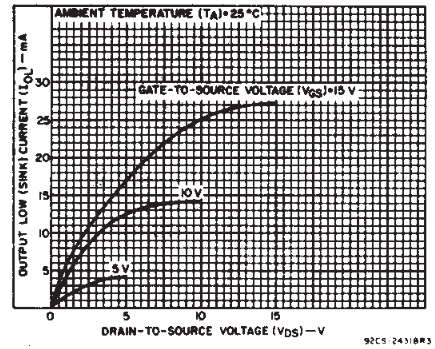


Fig. 2 — Typical output low (sink) current characteristics.

RECOMMENDED OPERATING CONDITIONS at T_A = 25°C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC		V_{DD} (V)	LIMITS Min.	LIMITS Max.	UNITS
Supply-Voltage Range (For T_A = Full Package-Temperature Range)			3	18	V
Clock Pulse Width,	t_WCL	5 10 15	180 80 50	– – –	ns
Clock Rise and Fall Time,	t_rCL, t_fCL	5 10 15	– – –	15 6 2	µs
Clock Input Frequency,	f_{CL}	5 10 15	DC	3 6 8.5	MHz
Data Setup Time,	t_{SU}	5 10 15	70 40 30	– – –	ns
Reset Pulse Width,	t_WR	5 10 15	200 80 60	– – –	ns

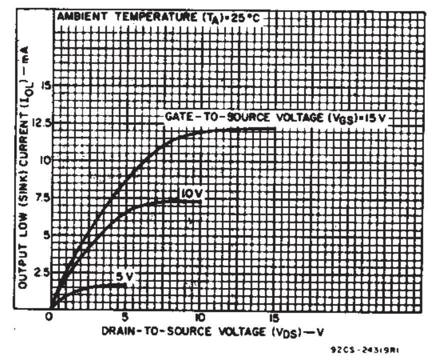


Fig. 3 — Minimum output low (sink) current characteristics.

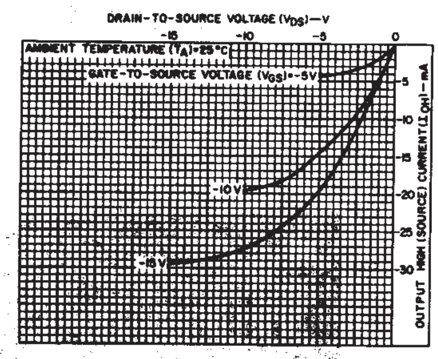


Fig. 4 — Typical output high (source) current characteristics.

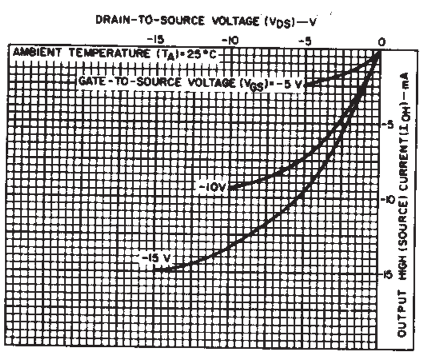


Fig. 5 — Minimum output high (source) current characteristics.

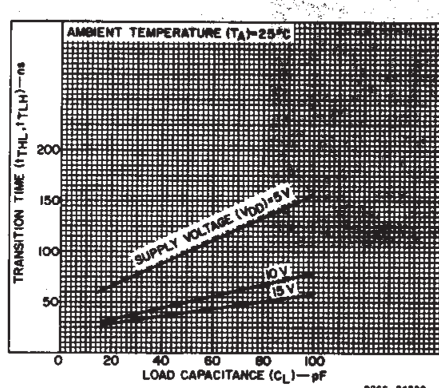


Fig. 6 — Typical transition time as a function of load capacitance.

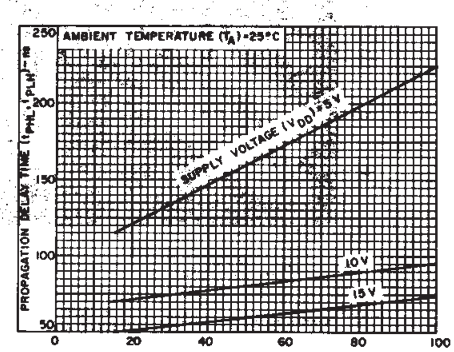
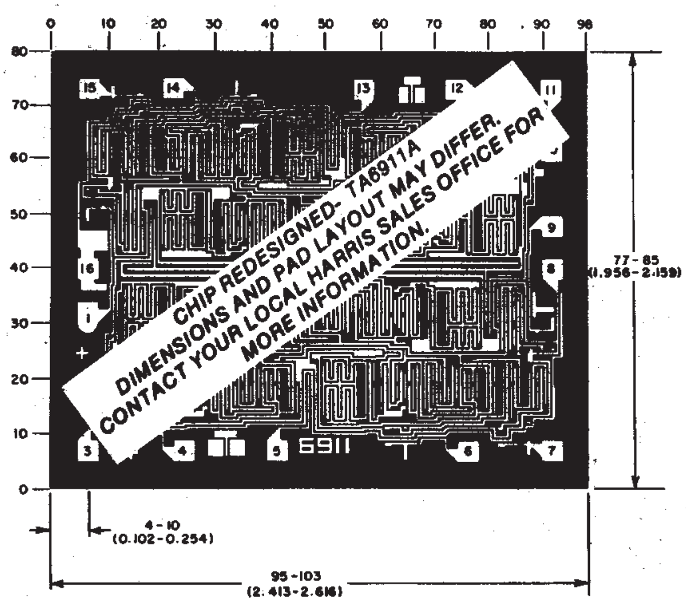


Fig. 7 — Typical propagation delay time as a function of load-capacitance.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	+25 Min.	+25 Typ.	+25 Max.	
Quiescent Device Current, I_{DD} Max.	–	0,5	5	5	5	150	150	–	0.04	5	µA
	–	0,10	10	10	10	300	300	–	0.04	10	
	–	0,15	15	20	20	600	600	–	0.04	20	
	–	0,20	20	100	100	3000	3000	–	0.08	100	
Output Low (Sink) Current I_{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Output High (Source) Current, I_{OH} Min.	4.6	0,5	5	−0.64	−0.61	−0.42	−0.36	−0.51	−1	–	
	2.5	0,5	5	−2	−1.8	−1.3	−1.15	−1.6	−3.2	–	
	9.5	0,10	10	−1.6	−1.5	−1.1	−0.9	−1.3	−2.6	–	
	13.5	0,15	15	−4.2	−4	−2.8	−2.4	−3.4	−6.8	–	
Output Voltage: Low-Level, V_{OL} Max.	–	0,5	5	0.05				–	0	0.05	V
	–	0,10	10	0.05				–	0	0.05	
	–	0,15	15	0.05				–	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	–	0,5	5	4.95				4.95	5	–	
	–	0,10	10	9.95				9.95	10	–	
	–	0,15	15	14.95				14.95	15	–	
Input Low Voltage, V_{IL} Max.	0.5, 4.5	–	5	1.5				–	–	1.5	V
	1, 9	–	10	3				–	–	3	
	1.5,13.5	–	15	4				–	–	4	
Input High Voltage, V_{IH} Min.	0.5, 4.5	–	5	3.5				3.5	–	–	
	1, 9	–	10	7				7	–	–	
	1.5,13.5	–	15	11				11	–	–	
Input Current I_{IN} Max.	–	0,18	18	±0.1	±0.1	±1	±1	–	$\pm10^{-5}$	±0.1	µA



Photograph of Chip Layout for CD4015B.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

DYNAMIC ELECTRICAL CHARACTERISTICS *at T_A = 25°C, Input t_r,t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ*

CHARACTERISTIC	TEST CONDITIONS V_{DD} (V)	LIMITS MIN.	LIMITS TYP.	LIMITS MAX.	UNITS
CLOCKED OPERATION					
Propagation Delay Time, T_{PHL}, T_{PLH}	5	—	160	320	ns
	10	—	80	160	
	15	—	60	120	
Transition Time, t_{THL}, t_{TLH}	5	—	100	200	
	10	—	50	100	
	15	—	40	80	
Minimum Clock Pulse Width, t_WCL	5	—	90	180	
	10	—	40	80	
	15	—	25	50	
Clock Rise and Fall Time, t_rCL, t_fCL*	5	—	—	15	µs
	10	—	—	6	
	15	—	—	2	
Minimum Data Setup Time, tSU	5	—	35	70	ns
	10	—	20	40	
	15	—	15	30	
Minimum Data Hold Time, t_H	5	—	—	0	
	10	—	—	0	
	15	—	—	0	
Maximum Clock Input Frequency, f_{CL}	5	3	6	—	MHz
	10	6	12	—	
	15	8.5	17	—	
Input Capacitance, C_{IN}	Any Input	—	5	7.5	pF
RESET OPERATION					
Propagation Delay Time, T_{PHL}, T_{PLH}	5	—	200	400	ns
	10	—	100	200	
	15	—	80	160	
Minimum Reset Pulse Width, t_WR	5	—	100	200	
	10	—	40	80	
	15	—	30	60	

*If more than one unit is cascaded t_rCL should be made less than or equal to the sum of the transition time and the fixed propagation delay of the output of the driving stage for the estimated capacitive load.

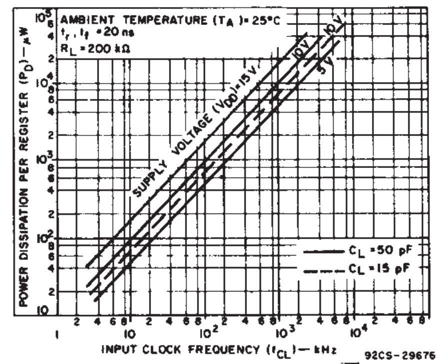


Fig. 8 – Typical power dissipation as a function of frequency.

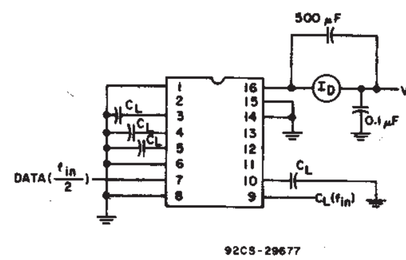


Fig. 9 – Power dissipation test circuit.

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COMMERCIAL CMOS HIGH VOLTAGE ICs

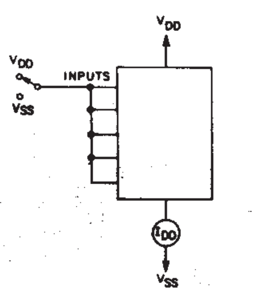

Fig. 10 – Quiescent device current test circuit.

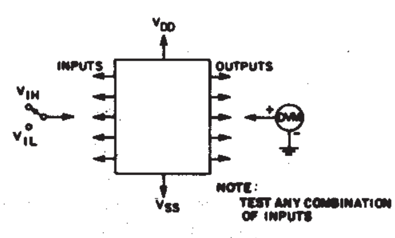

Fig. 11 – Input voltage test circuit.

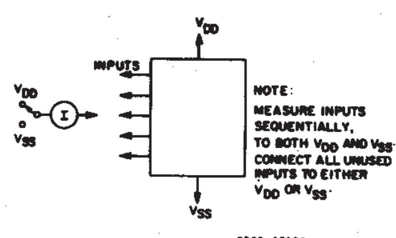

Fig. 12 – Input current test circuit.

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